Filing Date: 1/6/2004

SHEET 1 OF 1 INFORMATION DISCLOSURE SERIAL NO. ATTY. DOCKET NO. 60188-745 CITATION IN AN 751,523 **APPLICATION APPLICANT** Takaki YOSHIDA **GROUP** FILING DATE (PTO-1449) 2825 January 06, 2004 U.S. PATENT DOCUMENTS EXAMINER'S **Publication Date** Document Number Name of Patentee or Applicant of Cited Pages, Columns, Lines, Where INITIALS MM-DD-YYYY Relevant Passages or Relevant Document CITE Number-Kind Code2 (# known) Figures Appear 10/30/2001 US 6,311,147 B1 Tuan et al. US 6,453,443 B1 09/17/2002 Chen et al. US FOREIGN PATENT DOCUMENTS **EXAMINER'S** Foreign Patent Document Publication Date Name of Patentee or Pages, Columns, Lines Translation INITIALS CITE Applicant of Cited Document Where Relevant Country Codes - Number 4 - Kind MM-DD-YYYY Codes (if known) Figures Appear NO. Yes Nο JP 7-239865 (Japan w/English Abstract) 09/12/1995 MATSUSHITA ELECTRIC IND CO LTD OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, **EXAMINER'S** INITIALS journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where CITE Takaki YOSHIDA et al., "A New Approach for Low Power Scan Testing", ITC International Test Conference, Copyright 2003, IEEE, pd. 480-487. Phallaka Kike

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line tylrough citation if not in conformance and not considered.

Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.